FAIRCHILD

SEMICONDUCTOR TM

January 1990 Revised November 1999

74ACQ574 • 74ACTQ574 Quiet Series[™] Octal D-Type Flip-Flop with 3-STATE Outputs

General Description

The ACQ/ACTQ574 is a high-speed, low-power octal D-type flip-flop with a buffered Common Clock (CP) and a buffered common Output Enable ($\overline{\text{OE}}$). The information presented to the D inputs is stored in the flip-flops on the LOW-to-HIGH clock (CP) transition.

ACQ/ACTQ574 utilizes FACT Quiet Series™ technology to guarantee quiet output switching and improve dynamic threshold performance. FACT Quiet Series features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

The ACQ/ACTQ574 is functionally identical to the ACTQ374 but with different pin-out.

Features

- I_{CC} and I_{OZ} reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Inputs and outputs on opposite sides of the package allowing easy interface with microprocessors
- Functionally identical to the ACQ/ACTQ374
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Faster prop delays than the standard AC/ACT574

Ordering Code:

Order Number	Package Number	Package Description
74ACQ574SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACQ574SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACQ574PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
74ACTQ574SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACTQ574SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACTQ574PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Device also available in Tape and Reel. Specify by appending suffix "X" to the ordering code.

Connection Diagram

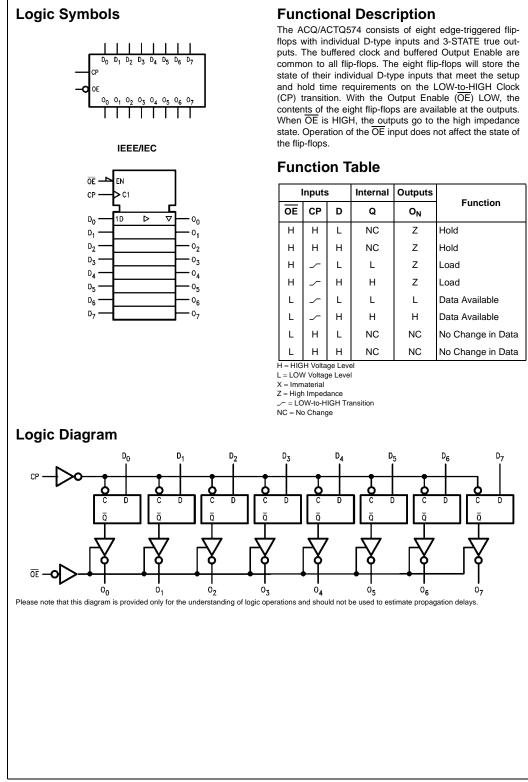
	_		_	
ŌE —	1	\bigcirc	20	-v _{cc}
D ₀ —	2		19	-00
-0 D1	3		18	-0.
D ₂	4		17	-0,
D3	5		16	-0,
D₄ —	6		15	-0 ₄
D ₅ -	7		14	-05
D ₆ -	8		13	-0 ₆
D7 -	9		12	-07
GND -	10		11	- CP

Pin Descriptions

Pin Names Description				
D ₀ -D ₇	Data Inputs			
СР	Clock Pulse Input			
OE	3-STATE Output Enable Input			
O ₀ -O ₇	3-STATE Outputs			

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Absolute Maximum F	Ratings(Note 1)	Recommended Operat	ting
Supply Voltage (V _{CC})	-0.5V to +7.0V	Conditions	
DC Input Diode Current (I _{IK})		Supply Voltage (V _{CC})	
$V_{l} = -0.5V$	–20 mA	ACQ	2.0V to 6.0V
$V_I = V_{CC} + 0.5V$	+20 mA	ACTQ	4.5V to 5.5V
DC Input Voltage (VI)	$-0.5V$ to $V_{CC} + 0.5V$	Input Voltage (V _I)	0V to V _{CC}
DC Output Diode Current (I _{OK})		Output Voltage (V _O)	0V to V _{CC}
$V_0 = -0.5V$	–20 mA	Operating Temperature (T _A)	-40°C to +85°C
$V_O = V_{CC} + 0.5V$	+20 mA	Minimum Input Edge Rate $\Delta V / \Delta t$	
DC Output Voltage (V _O)	$-0.5V$ to $V_{CC} + 0.5V$	ACQ Devices	
DC Output Source		V_{IN} from 30% to 70% of V_{CC}	
or Sink Current (I _O)	±50 mA	V _{CC} @ 3.0V, 4.5V, 5.5V	125 mV/ns
DC V _{CC} or Ground Current		Minimum Input Edge Rate $\Delta V/\Delta t$	
per Output Pin (I _{CC} or I _{GND})	±50 mA	ACTQ Devices	
Storage Temperature (T _{STG})	$-65^{\circ}C$ to $+150^{\circ}C$	V _{IN} from 0.8V to 2.0V	
DC Latch-Up Source or		V _{CC} @ 4.5V, 5.5V	125 mV/ns
Sink Current	±300 mA	Note 1: Absolute maximum ratings are those va	
Junction Temperature (T _J)		to the device may occur. The databook specific out exception, to ensure that the system design	
PDIP	140°C	supply, temperature, and output/input loading v recommend operation of FACT™ circuits outside	ariables. Fairchild does not

DC Electrical Characteristics for ACQ

Symbol	Parameter	v _{cc}	T _A =	+ 25°C	$T_A = -40^{\circ}C$ to $+85^{\circ}C$	Units	Conditions	
Symbol	Faranieter	(V)	Тур	Gu	aranteed Limits	Units	Conditions	
VIH	Minimum HIGH Level	3.0	1.5	2.1	2.1		V _{OUT} = 0.1V	
	Input Voltage	4.5	2.25	3.15	3.15	V	or $V_{CC} - 0.1V$	
		5.5	2.75	3.85	3.85			
VIL	Maximum LOW Level	3.0	1.5	0.9	0.9		$V_{OUT} = 0.1V$	
	Input Voltage	4.5	2.25	1.35	1.35	V	or $V_{CC} - 0.1V$	
		5.5	2.75	1.65	1.65			
V _{OH}	Minimum HIGH Level	3.0	2.99	2.9	2.9			
	Output Voltage	4.5	4.49	4.4	4.4	V	$I_{OUT} = -50 \ \mu A$	
		5.5	5.49	5.4	5.4			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		2.56	2.46		$I_{OH} = -12 \text{ mA}$	
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$	
		5.5		4.86	4.76		$I_{OH} = -24 \text{ mA}$ (Note 2	
V _{OL}	Maximum LOW Level	3.0	0.002	0.1	0.1			
	Output Voltage	4.5	0.001	0.1	0.1	V	$I_{OUT} = 50 \ \mu A$	
		5.5	0.001	0.1	0.1			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		0.36	0.44		$I_{OL} = 12 \text{ mA}$	
		4.5		0.36	0.44	V	$I_{OL} = 24 \text{ mA}$	
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 2)	
IN	Maximum Input	5.5		±0.1	±1.0	μA	$V_{I} = V_{CC_{i}}$ GND	
(Note 4)	Leakage Current	5.5		±0.1	1.0	μΑ	VI - VCC, GND	
OLD	Minimum Dynamic	5.5			75	mA	V _{OLD} = 1.65V Max	
OHD	Output Current (Note 3)	5.5			-75	mA	V _{OHD} = 3.85V Min	
сс	Maximum Quiescent	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$	
(Note 4)	Supply Current	5.5		7.0	-0.0	μη	or GND	
oz	Maximum 3-STATE						V_{I} (OE) = V_{IL} , V_{IH}	
	Leakage Current	5.5		±0.25	±2.5	μΑ	$V_I = V_{CC}, GND$	
							$V_0 = V_{CC}$, GND	

DC E	lectrical Charact	teristics	for AC	CQ (Cont	inued)			
0h.al	Deservation	V _{CC}	T _A =	+ 25°C	$T_A = -40^{\circ}C$ to $+85^{\circ}C$	Unite		
Symbol	Parameter	(V)	Тур	Gu	aranteed Limits	Units	Conditions	
V _{OLP}	Quiet Output	5.0	1.1	4.5		V	Figure 1, Figure 2	
	Maximum Dynamic V _{OL}	5.0		1.5		v	(Note 5)(Note 6)	
V _{OLV}	Quiet Output	5.0	-0.6	4.0		V	Figure 1, Figure 2	
	Minimum Dynamic V _{OL}	5.0		-1.2		v	(Note 5)(Note 6)	
VIHD	Minimum HIGH Level	5.0	3.1	3.5		V	(Nata E)(Nata Z)	
	Dynamic Input Voltage	5.0	3.1	3.5		v	(Note 5)(Note 7)	
V _{ILD}	Maximum LOW Level	5.0	1.0	4.5		V	(Nata E)(Nata Z)	
	Dynamic Input Voltage	5.0	1.9	1.5		V	(Note 5)(Note 7)	

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

Note 4: $I_{\rm IN}$ and $I_{\rm CC}$ @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V $V_{\rm CC}.$

Note 5: DIP package.

Note 6: Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.

Note 7: Maximum number of data inputs (n) switching. (n–1) inputs switching 0V to 5V (ACQ). Input-under-test switching: 5V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

DC Electrical Characteristics for ACTQ

Symbol	Parameter	v _{cc}	T _A =	+ 25°C	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Units	Conditions	
Symbol	Farameter	(V)	(V) Typ		Guaranteed Limits		Conditions	
VIH	Minimum HIGH Level	4.5	1.5	2.0	2.0	V	$V_{OUT} = 0.1V$	
	Input Voltage	5.5	1.5	2.0	2.0	V	or $V_{CC} - 0.1V$	
VIL	Maximum LOW Level	4.5	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$	
	Input Voltage	5.5	1.5	0.8	0.8	v	or $V_{CC} - 0.1V$	
V _{OH}	Minimum HIGH Level	4.5	4.49	4.4	4.4	V	I _{OUT} = -50 μA	
	Output Voltage	5.5	5.49	5.4	5.4	v	i _{OUT} = -50 μA	
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		4.5		3.85	3.76	V	I _{OH} =-24 mA	
		5.5		4.86	4.76		I _{OH} =-24 mA (Note 8)	
V _{OL}	Maximum LOW Level	4.5	0.001	0.1	0.1	V	I _{OUT} = 50 μA	
	Output Voltage	5.5	0.001	0.1	0.1	v	i _{OUT} = ου μΑ	
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		4.5		0.36	0.44	V	I _{OL} = 24 mA	
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 8)	
I _{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0	μA	$V_I = V_{CC}, GND$	
I _{OZ}	Maximum 3-STATE	5.5		±0.25	±2.5	μA	$V_I = V_{IL}, V_{IH}$	
	Leakage Current	5.5		10.25	12.0	μΛ	$V_{O} = V_{CC}, \text{ GND}$	
I _{CCT}	Maximum I _{CC} /Input	5.5	0.6		1.5	mA	$V_I = V_{CC} - 2.1V$	
I _{OLD}	Minimum Dynamic	5.5			75	mA	V _{OLD} = 1.65V Max	
I _{OHD}	Output Current (Note 9)	5.5			-75	mA	V _{OHD} = 3.85V Min	
Icc	Maximum Quiescent	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$	
	Supply Current	0.0		7.0	-0.0	μη	or GND	
V _{OLP}	Quiet Output	5.0	1.1	1.5		V	Figure 1, Figure 2	
	Maximum Dynamic V _{OL}	0.0		1.5		v	(Note 10)(Note 11)	
V _{OLV}	Quiet Output	5.0	-0.6	-1.2		V	Figure 1, Figure 2	
	Minimum Dynamic V _{OL}	3.0	-0.0	-1.2		v	(Note 10)(Note 11)	
V _{IHD}	Minimum HIGH Level	5.0	1.9	2.2		V	(Note 10)(Note 12)	
	Dynamic Input Voltage	5.0	1.5	2.2		v		
V _{ILD}	Maximum LOW Level	5.0	1.2	0.8		V	(Note 10)(Note 12)	
	Dynamic Input Voltage	5.0	1.2	0.0		v	(14010 10)(14010 12)	

Note 8: All outputs loaded; thresholds on input associated with output under test.

Note 9: Maximum test duration 2.0 ms, one output loaded at a time.

Note 10: DIP package.

Note 11: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

DC Electrical Characteristics for ACTQ (Continued)

Note 12: Max number of data inputs (n) switching. (n–1) inputs switching 0V to 3V (ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

AC Electrical Characteristics for ACQ

		V _{cc}		$T_A = +25^{\circ}C$		$T_A = -40^\circ$	C to +85°C	
Symbol	Parameter	(V)	C _L = 50 pF			C _L =	Units	
		(Note 13)	Min	Тур	Max	Min	Max	
f _{MAX}	Maximum Clock	3.3	75			70		MHz
	Frequency	5.0	90			85		IVITIZ
t _{PLH}	Propagation Delay	3.3	3.0	9.5	13.0	3.0	13.5	
t _{PHL}	CP to On	5.0	2.0	6.5	8.5	2.0	9.0	ns
t _{PZH}	Output Enable Time	3.3	3.0	9.5	13.0	3.0	13.5	ns
t _{PZL}		5.0	2.0	6.5	8.5	2.0	9.0	115
t _{PHZ}	Output Disable Time	3.3	1.0	9.5	14.5	1.0	15.0	ns
t _{PLZ}		5.0	1.0	8.0	9.5	1.0	10.0	115
t _{OSHL}	Output to Output Skew (Note 14)	3.3		1.0	1.5		1.5	
t _{OSLH}	CP to On	5.0		0.5	1.0		1.0	ns

Note 13: Voltage Range 5.0 is $5.0V\pm0.5V$

Voltage Range 3.3 is 3.3V \pm 0.3V

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements for ACQ

Symbol	Parameter	v _{cc} (V)	T _A = +25°C C _L = 50 pF		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $C_L = 50 \text{ pF}$	Units
		(Note 15)	Тур	Guar	anteed Minimum	
t _S	Setup Time, HIGH or LOW	3.3	0	3.0	3.0	
	D _n to CP	5.0	0	3.0	3.0	ns
t _H	Hold Time, HIGH or LOW	3.3	0	1.5	1.5	
	D _n to CP	5.0	0	1.5	1.5	ns
**	CP Pulse Width,	3.3	2.0	4.0	4.0	
	HIGH or LOW	5.0	2.0	4.0	4.0	ns

Note 15: Voltage Range 5.0 is $5.0V\pm0.5V$

Voltage Range 3.3 is 3.3V \pm 0.3V

AC Electrical Characteristics for ACTQ

Symbol	Parameter	V _{CC} (V)	T _A = +25°C C _L = 50 pF			T _A = -40°C to +85°C C _L = 50 pF		Units
		(Note 16)	Min	Тур	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	5.0	85			80		MHz
t _{PLH} t _{PHL}	Propagation Delay CP to O _n	5.0	2.0	7.0	9.0	2.0	9.5	ns
t _{PZH} t _{PZL}	Output Enable Time	5.0	2.0	7.0	9.0	2.0	9.5	ns
t _{PHZ} t _{PLZ}	Output Disable Time	5.0	1.0	8.0	10.0	1.0	10.5	ns
t _{OSHL} t _{OSLH}	Output to Output Skew (Note 17) CP to \overline{O}_n	5.0		0.5	1.0		1.0	ns

Note 16: Voltage Range 5.0 is 5.0V \pm 0.5V.

Note 17: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

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AC Operating Requirements for ACTQ

Symbol	Parameter	V _{cc} (V)	T _A = +25°C C _L = 50 pF		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $C_L = 50 \text{ pF}$	Units
		(Note 18)	Тур	Guara	anteed Minimum	
ts	Setup Time, HIGH or LOW D _n to CP	5.0	0	3.0	3.0	ns
н	Hold Time, HIGH or LOW D _n to CP	5.0	0	1.5	1.5	ns
W	CP Pulse Width, HIGH or LOW	5.0	2.0	4.0	4.0	ns

Capacitance

Symbol	Parameter	Тур	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	40.0	pF	$V_{CC} = 5.0V$

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

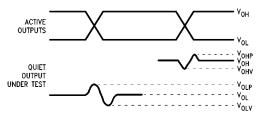
Hewlett Packard Model 8180A Word Generator

PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50 pF, 500 Ω .
- Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
- Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
- Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



Note 19: V_{OHV} and V_{OLP} are measured with respect to ground reference. Note 20: Input pulses have the following characteristics: f = 1 MHz, $t_r = 3 \text{ ns}, t_f = 3 \text{ ns}, skew < 150 \text{ ps}.$

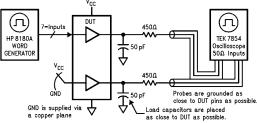
FIGURE 1. Quiet Output Noise Voltage Waveforms

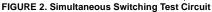
 V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV} :

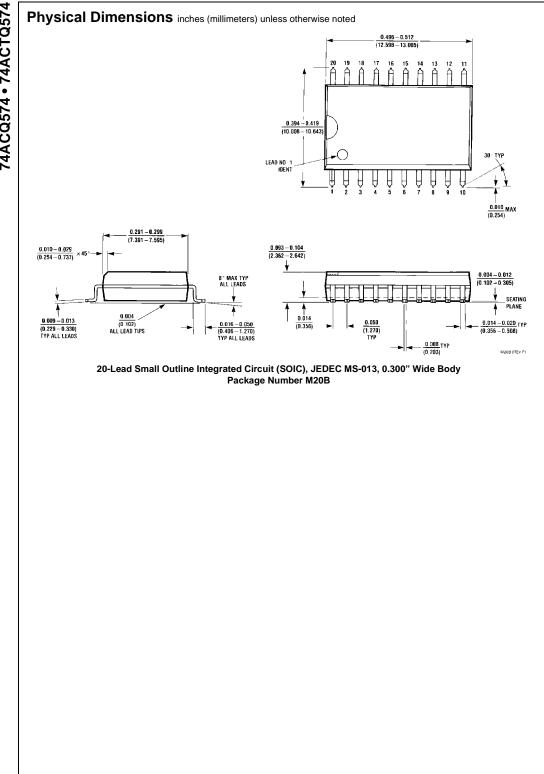
- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the worst case for active and enable transition. Measure V_{OHP} and V_{OHV} on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

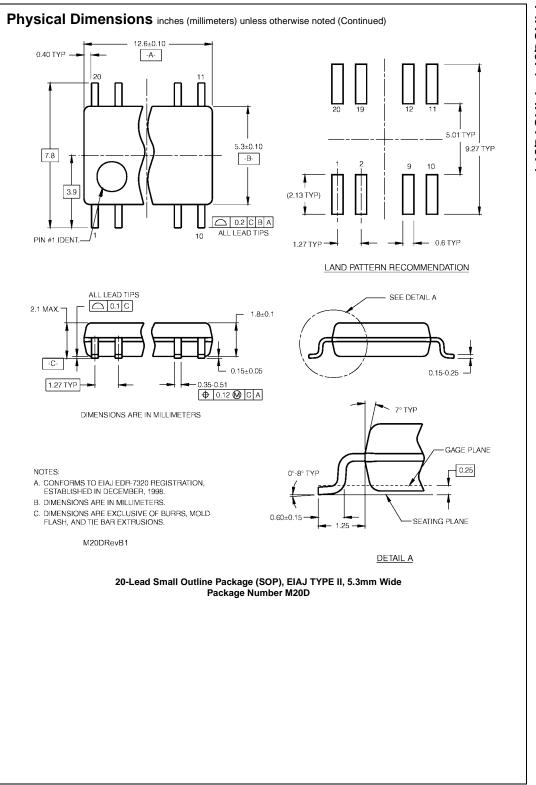
- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next decrease the input HIGH voltage level, V_{IH}, until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.







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